



SEMiX® 5

Trench IGBT Modules

Engineering Sample SEMiX305GARL07E3

Target Data

Features

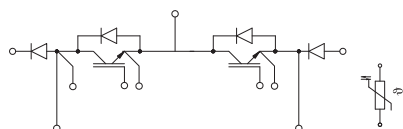
- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT Trench Gate Technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

Typical Applications*

- UPS
- 3 Level Inverters

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
- Dynamic data are estimated
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



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Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
IGBT			
V_{CES}	$T_j = 25^\circ\text{C}$	650	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	353
		$T_c = 80^\circ\text{C}$	265
I_{Cnom}		300	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	900	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 360\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 650\text{ V}$	$T_j = 150^\circ\text{C}$	6
			μs
T_j		-40 ... 175	$^\circ\text{C}$
Inverse diode			
V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	86
		$T_c = 80^\circ\text{C}$	64
I_{Fnom}		50	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	100	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	550	A
T_j		-40 ... 175	$^\circ\text{C}$
Freewheeling diode			
V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	355
		$T_c = 80^\circ\text{C}$	259
I_{Fnom}		300	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	600	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	2160	A
T_j		-40 ... 175	$^\circ\text{C}$
Module			
$I_{t(RMS)}$		400	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, t = 1 min	4000	V

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 300\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.45	1.90	V
		$T_j = 150^\circ\text{C}$	1.69	2.10	V
V_{CE0}	chipelevel	$T_j = 25^\circ\text{C}$	0.90	1.00	V
		$T_j = 150^\circ\text{C}$	0.82	0.90	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.83	3.0	m Ω
		$T_j = 150^\circ\text{C}$	2.9	4.0	m Ω
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 4.8\text{ mA}$	5.1	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 650\text{ V}$	$T_j = 25^\circ\text{C}$	0.10	0.3	mA
		$T_j = 150^\circ\text{C}$	-	-	mA
C_{ies}	$V_{CE} = 25\text{ V}$		18.5		nF
C_{oes}	$V_{GE} = 0\text{ V}$		1.16		nF
C_{res}			0.55		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$		3940		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		1.0		Ω



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- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

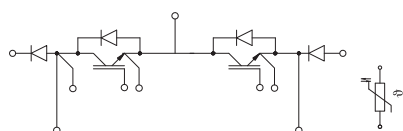
Typical Applications*

- UPS
- 3 Level Inverters

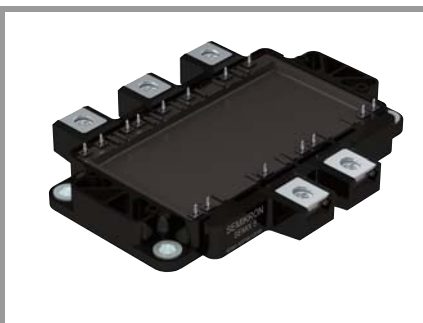
Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
$t_{d(on)}$	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		220		ns
t_r	$I_C = 300\text{ A}$	$T_j = 150^\circ\text{C}$		220		ns
E_{on}	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$		21.3		mJ
$t_{d(off)}$	$R_{G\ on} = 13\ \Omega$	$T_j = 150^\circ\text{C}$		1120		ns
t_f	$R_{G\ off} = 13\ \Omega$	$T_j = 150^\circ\text{C}$		103		ns
E_{off}	$di/dt_{on} = 2038\text{ A}/\mu\text{s}$ $di/dt_{off} = 3960\text{ A}/\mu\text{s}$ $du/dt = 3052\text{ V}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		21.3		mJ
$R_{th(j-c)}$	per IGBT				0.18	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease}=0.81\text{ W/mK}$, thickness 50-100 μm)			0.066		K/W
$R_{th(c-s)}$	per IGBT ($\lambda=3.4\text{ W/mK}$)			t.b.d.		K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 50\text{ A}$	$T_j = 25^\circ\text{C}$		1.37	1.73	V
	$V_{GE} = 0\text{ V}$ chipllevel	$T_j = 150^\circ\text{C}$		1.35	1.72	V
V_{F0}	chipllevel	$T_j = 25^\circ\text{C}$		1.04	1.24	V
		$T_j = 150^\circ\text{C}$		0.85	0.99	V
r_F	chipllevel	$T_j = 25^\circ\text{C}$		6.7	9.8	m Ω
		$T_j = 150^\circ\text{C}$		10	15	m Ω
I_{RRM}	$I_F = 50\text{ A}$	$T_j = 150^\circ\text{C}$		-		A
Q_{rr}		$T_j = 150^\circ\text{C}$		-		μC
E_{rr}	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$				mJ
$R_{th(j-c)}$	per diode				0.81	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W/mK}$, thickness 50-100 μm)			0.082		K/W
$R_{th(c-s)}$	per diode ($\lambda=3.4\text{ W/mK}$)			t.b.d.		K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 300\text{ A}$	$T_j = 25^\circ\text{C}$		1.40	1.76	V
	$V_{GE} = 0\text{ V}$ chipllevel	$T_j = 150^\circ\text{C}$		1.39	1.77	V
V_{F0}	chipllevel	$T_j = 25^\circ\text{C}$		1.04	1.236	V
		$T_j = 150^\circ\text{C}$		0.85	0.99	V
r_F	chipllevel	$T_j = 25^\circ\text{C}$		1.19	1.76	m Ω
		$T_j = 150^\circ\text{C}$		1.79	2.6	m Ω
I_{RRM}	$I_F = 300\text{ A}$	$T_j = 150^\circ\text{C}$		141.4		A
Q_{rr}	$di/dt_{off} = 2038\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		28		μC
E_{rr}	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		4.7		mJ
$R_{th(j-c)}$	per diode				0.23	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W/mK}$, thickness 50-100 μm)			0.076		K/W
$R_{th(c-s)}$	per diode ($\lambda=3.4\text{ W/mK}$)			t.b.d.		K/W



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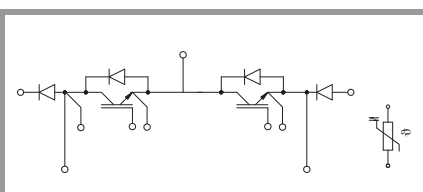
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Module						
L_{CE}				30		nH
$R_{CC'+EE'}$	measured per switch	$T_C = 25^\circ\text{C}$		0.8		m Ω
		$T_C = 125^\circ\text{C}$		1.1		m Ω
$R_{th(c-s)1}$	calculated without thermal coupling			0.018		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W/(m}^2\text{K)}$)			t.b.d.		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material			t.b.d.		K/W
M_s	to heat sink (M5)		3		6	Nm
M_t		to terminals (M6)	3		6	Nm
						Nm
W				398		g
Temperature Sensor						
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$			$3550 \pm 2\%$		K



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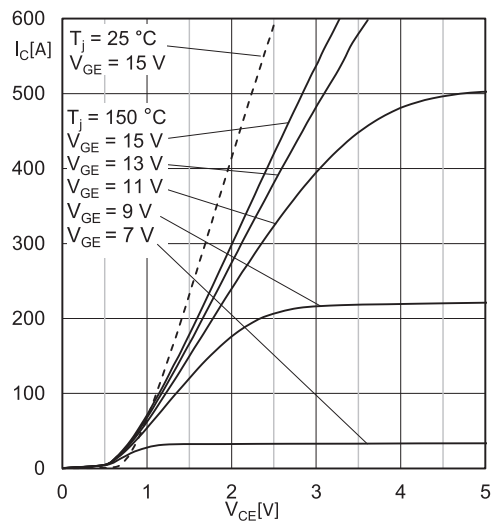


Fig. 1: Typ. output characteristic, inclusive $R_{CC+EE'}$

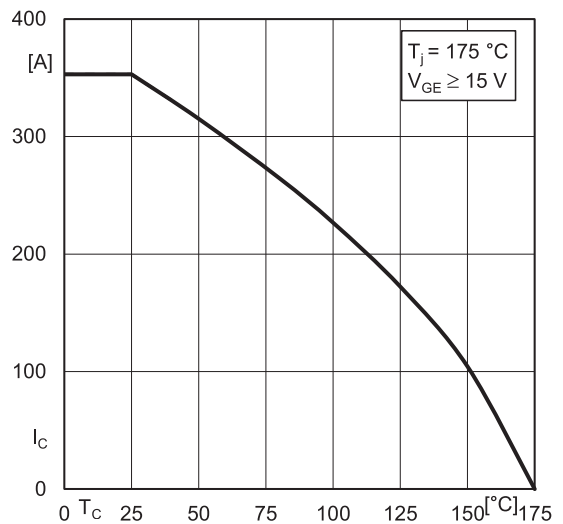


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

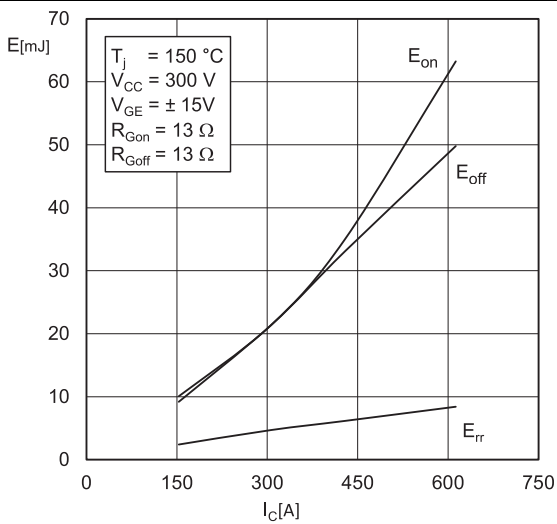


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

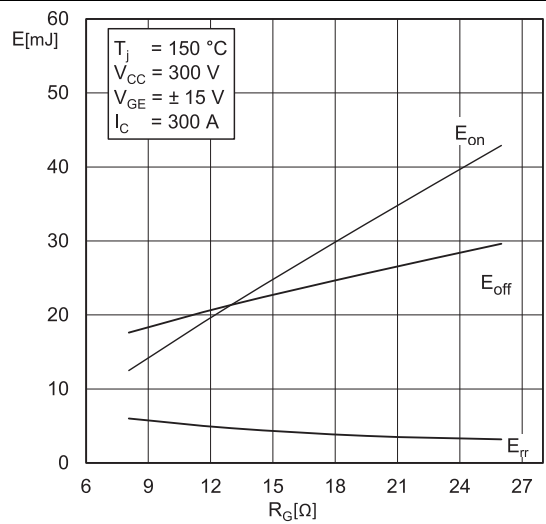


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

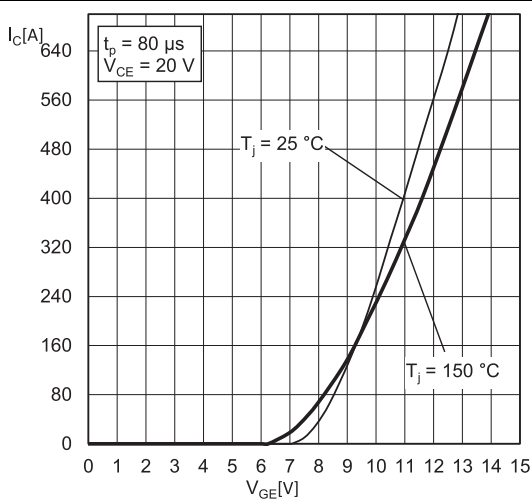


Fig. 5: Typ. transfer characteristic

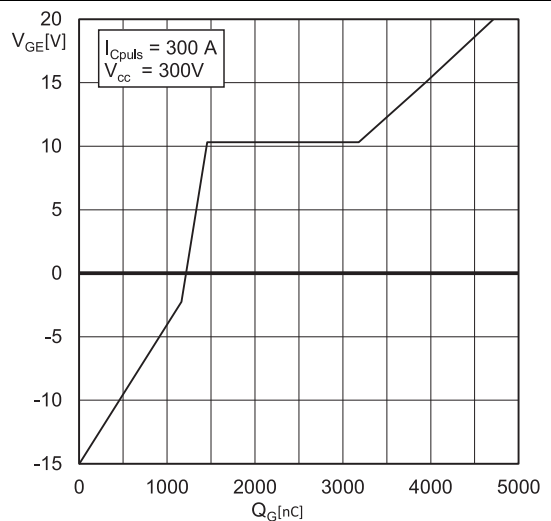


Fig. 6: Typ. gate charge characteristic

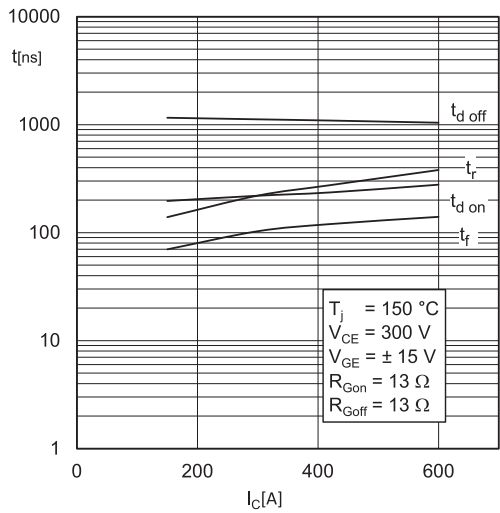


Fig. 7: Typ. switching times vs. I_C

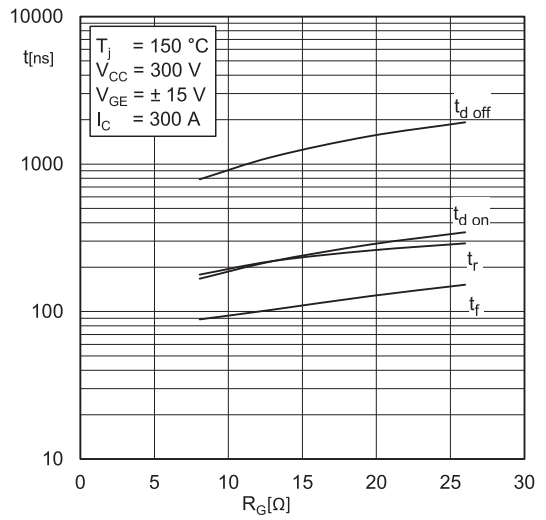


Fig. 8: Typ. switching times vs. gate resistor R_G

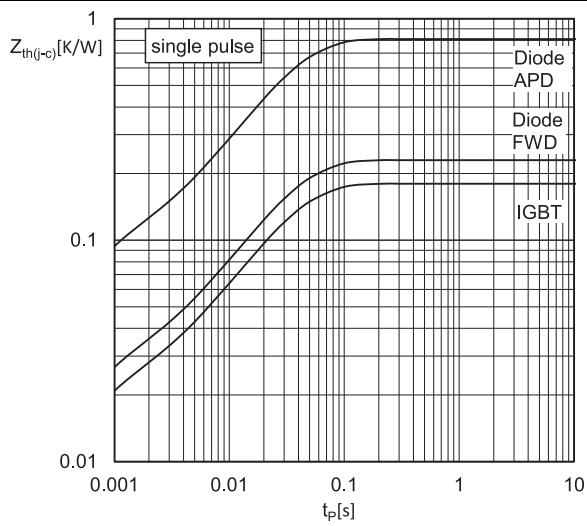


Fig. 9: Transient thermal impedance

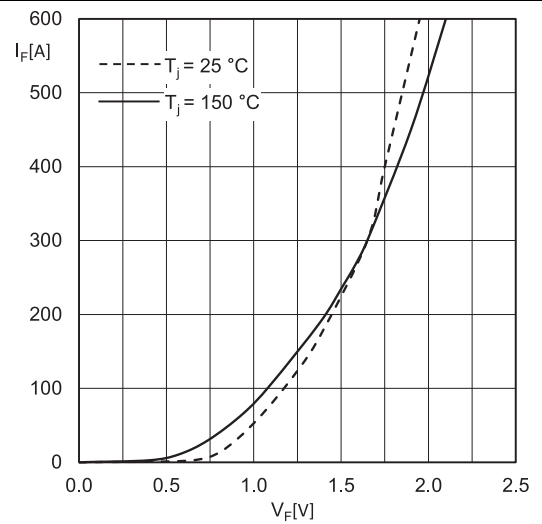


Fig. 10: Typ. FWD diode forward characteristic, incl. R_{CC} + EE'

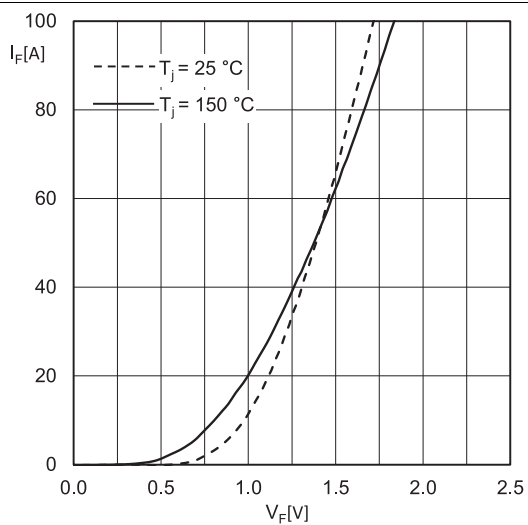
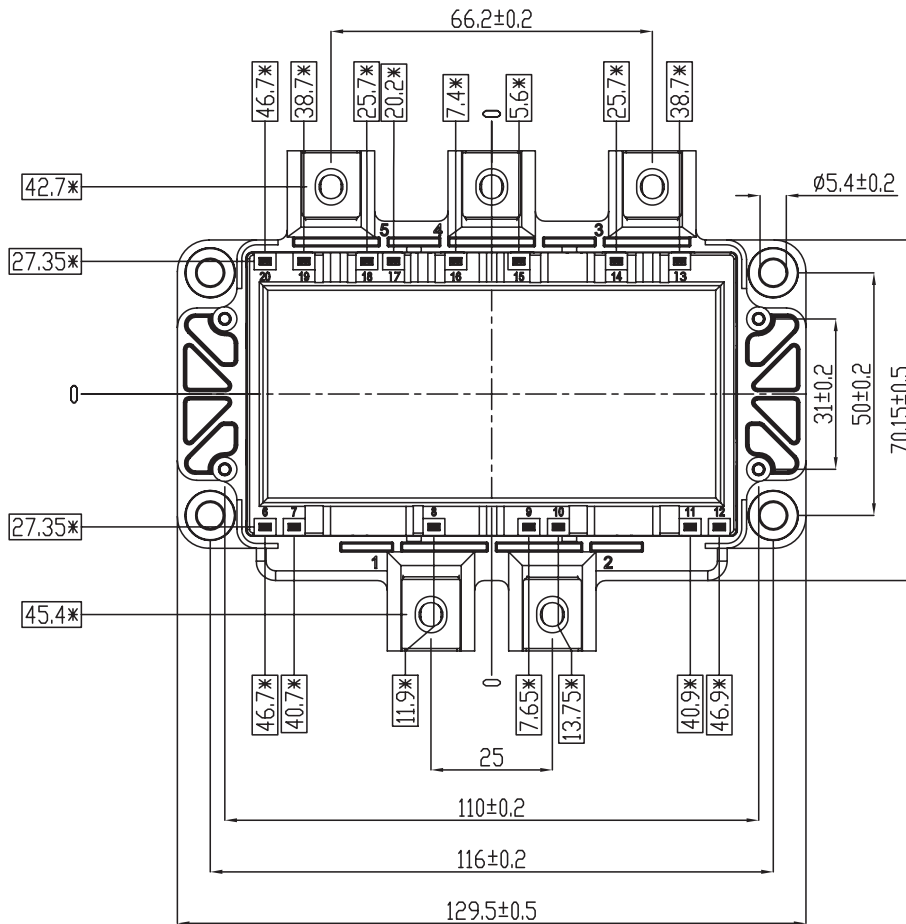
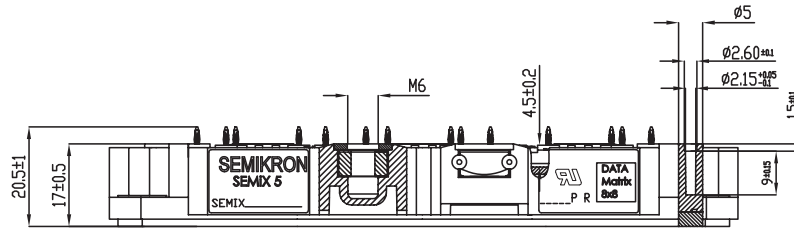


Fig. 11: Typ. inv. diode forward charact., incl. R_{CC} + EE'

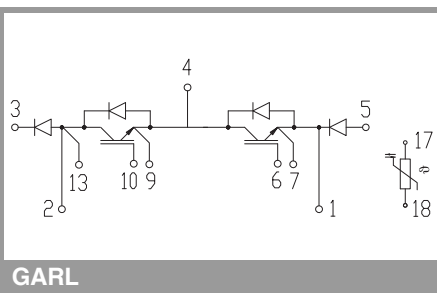
SEMiX305GARL07E3



* = All dimension with tolerance of ± 0.4

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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